Special Issue

Fault Diagnosis and Detection of Machinery

Message from the Guest Editors

This Special Issue focuses on sharing advances, results and perspectives in the field of condition monitoring of mechanical systems. Although most of the critical components have been widely analyzed, new applications are proposed in the industrial field and always pose new challenges to diagnostics in terms of complexity, harsh environment, and non-stationary working conditions, among others. The target of the Special Issue is to collect novel contributions for all the steps of the fault diagnosis and detection process. An indicative list may include the development of specific sensors, hardware setup, data analytics, physical modelling, data processing and data fusion. Papers on machine learning approaches to diagnostics are accepted but the physical parameters that determine the success of the methodology proposed should be evident. Although advances have been made in other fields—such as MCSA—this Special Issue is mainly focused on the vibration-based condition monitoring of mechanical/mechatronics systems. Other types of signals/sensors are allowed as long as they are necessary for the vibrational analysis.

Guest Editors

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Dr. Matteo Strozzi

Dr. Gianluca D'Elia

Deadline for manuscript submissions

closed (20 December 2024)

Applied Sciences

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About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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